

Thin-Film Measurement

*Perform Lab Tasks On-Line
With Extreme Accuracy*

Brimrose high-speed AOTF-NIR Thin-Film Analyzers perform laboratory tasks ON-LINE with extreme accuracy. To optimize the production process the instrument can be placed within production lines where accurate analytical monitoring of thin films or coatings is of importance.

The instrument can be used for on-line specification verification, coating thickness measurement of single layer or multi-layer coatings on films or papers, analyze and evaluate chemical compositions of coatings or films, monitor for residual solvents, curing time, etc.

The AOTF-NIR Thin-Film AOTF-NIR Spectrometers are totally insensitive to ambient light, immune to vibration, dust, dirt and designed to work reliable and without maintenance in the production environment. A novel optical design makes the measurements of thin films or coatings a cost effective method for quality control and waste reduction.

A Better Method

The Brimrose Luminar 4020 Thin-Film Analyzer is mounted permanently on the automatic rail for thin film and coating thickness analysis across the web.

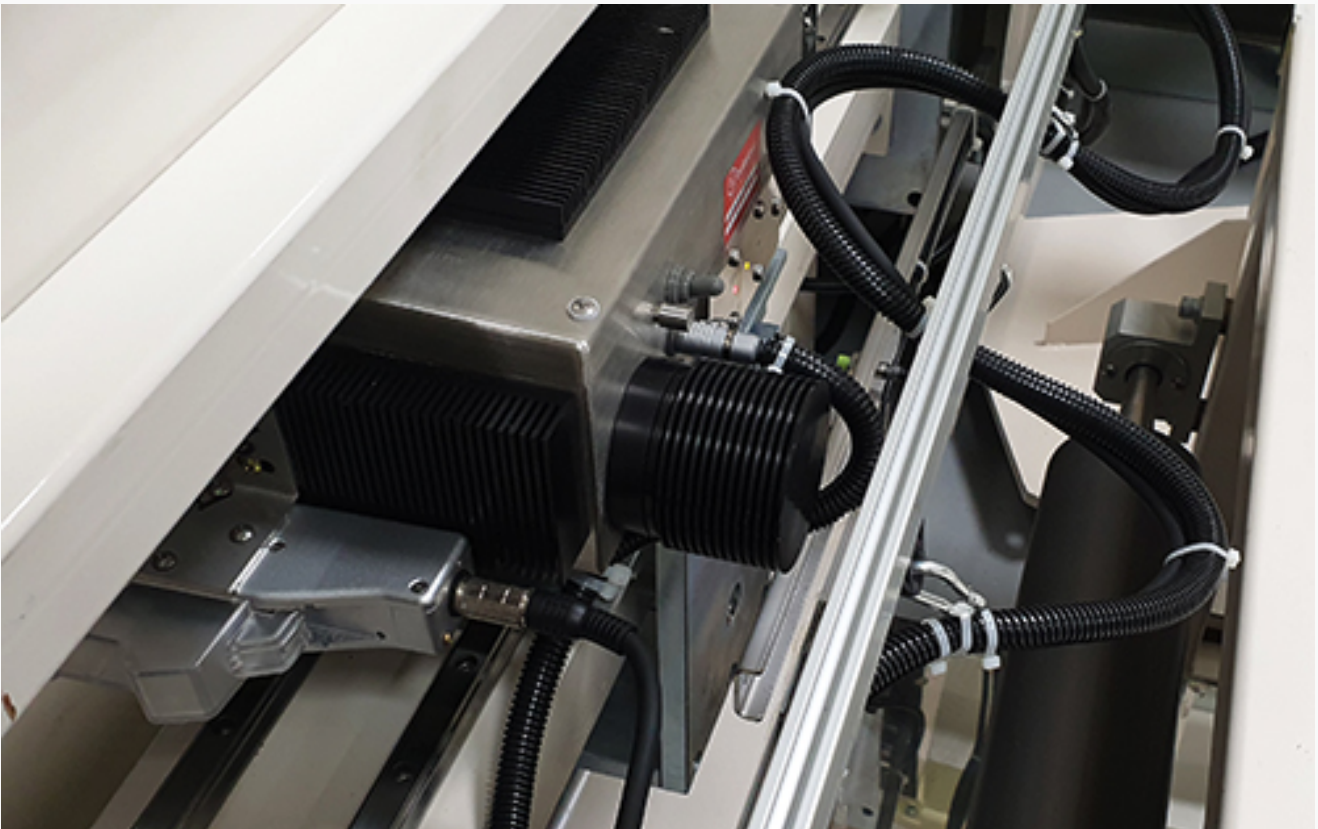


Luminar 4020 Thin-Film
AOTF-NIR Spectrometer

A Proven Benefit

Successful implementation of a Brimrose AOTF-NIR spectrometer results in:

- Non-contact solid state sensors with a compact, rugged design, providing rapid full spectrum scanning for demanding industrial use
- Mounted on a traveler and scan across the web or can be used for statistical spot measurements
- Be interfaced with the main plant PLC's or DCS for instant and / or automated process adjustments
- Huge savings in lab analysis - time and money for many customers around the world



On-Line Installation of Brimrose Luminar 4020 Thin-Film AOTF-NIR Spectrometer